

Notice of References Cited

Application/Control No.

10/564,742

Applicant(s)/Patent Under

Reexamination

ENDO ET AL.

Examiner

JACOB MARKS

Art Unit

1795

Page 1 of 1

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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N	CN 1416189	05-2003	China	Chen et al.	
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